

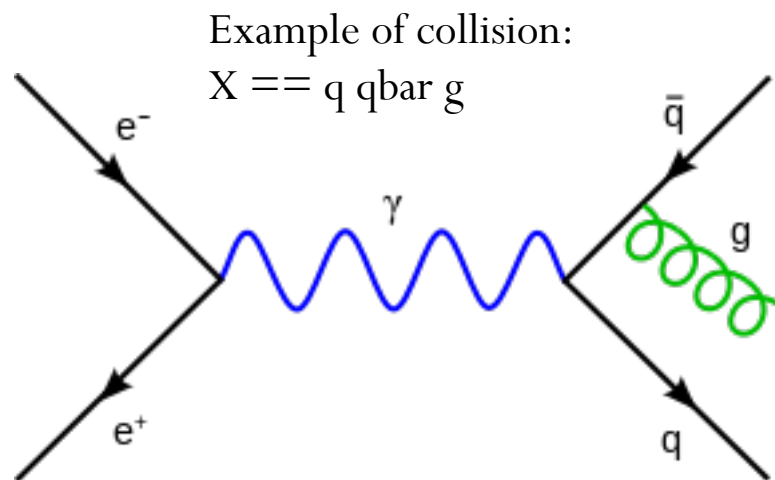
The Logic of an EPP experiment

“Logic” of an EPP experiment - I

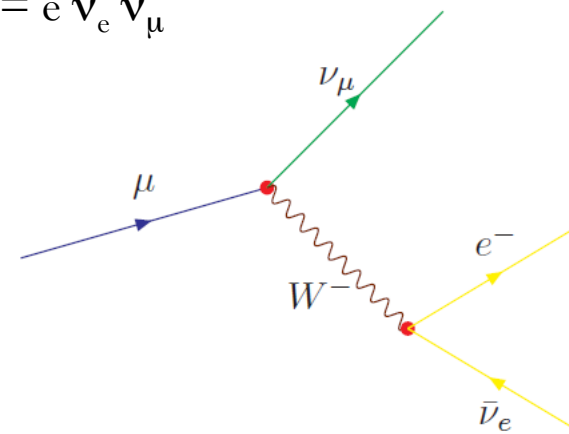
- Collision or decay: \rightarrow **process to look at**
 - **Initial state** (proj. + target) OR (decaying particle);
 - **Final state** X = all particles produced
- Quadri-momentum conservation should always be at work
- In principle there is no need to measure ALL final state particles: a final state could be: $\rightarrow \mu^+ \mu^- + X$ (“inclusive” search)
- Possible final states:
 - $a + b \rightarrow a + b$: **elastic collision** (e.g. $pp \rightarrow pp$)
 - $a + b \rightarrow X$: **inelastic collision** (e.g. $pp \rightarrow pp\pi^0$)
- The experimentalist should set-up an experimental procedure to select “**events**” with the final state he is searching, in such a way to count the number N_X of final states X.

Why count events ?

- Why count events ?
- Because QFT based models allow to predict quantities (like **cross-sections**, **decay widths** and **branching ratios**, see later) that are proportional to “**how probable is**” a given final state.



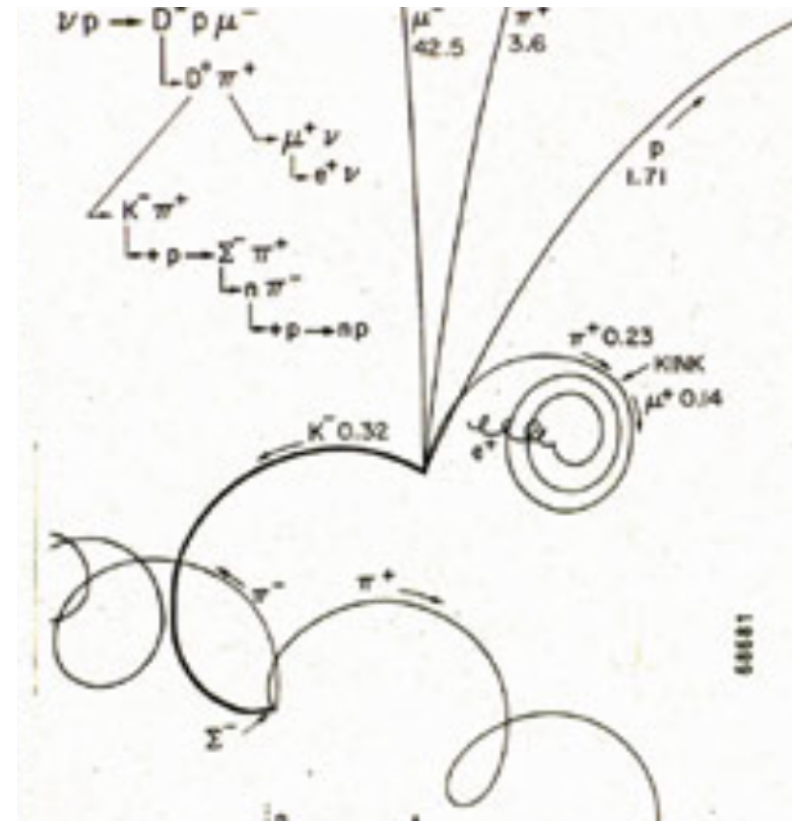
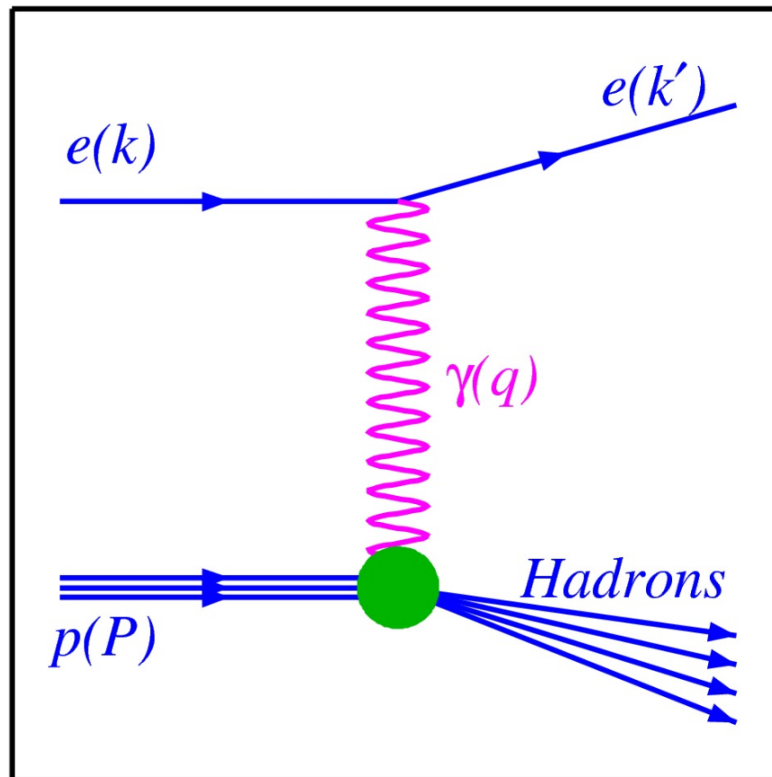
Example of decay:
 $X == e \nu_e \nu_\mu$



Event: a “photo” of a collision/decay

Inclusive Event: measure the electron only

Exclusive Event: measure all particles to “close” the kinematics



“Logic” of an EPP experiment - II

- An *ideal detector* allows to measure the quadri-momentum of each particle involved in the reaction.
 - Direction of flight;
 - Energy E and/or momentum modulus $|\mathbf{p}|$;
 - Which particle is (e.g. from independent measurements of E and $|\mathbf{p}|$ $m^2 = E^2 - |\mathbf{p}|^2$) \rightarrow Particle ID
- BUT for a *real detector*:
 - Not all quadri-momenta are measured: some particles are out of acceptance, or only some quantities are accessible, **inefficiencies**;
 - Measurements are affected by **resolution**
 - Sometimes the particle nature is “confused”

“Logic” of an EPP experiment - III

- Selection steps:

1. TRIGGER selection

- Retain only “interesting events”: from bubble chambers to electronic detectors
- → “logic-electronic” eye: decides in a short time $O(\mu\text{s})$ if the event is ok or not.
- In some cases (e.g. pp), it is crucial since interactions are so probable...
- LHC: every 25 ns is a bunch crossing giving rise to interactions: can I write 40 MHz on “tape”? A typical event has a size of 1 MB → 40 TB/s. Is it conceivable? And how many CPU will be needed to analyze these data? At LHC from 40 MHz to 200 Hz! Only one bunch crossing every 200000!
- “pre-scale” is an option
- e^+e^- : the situation is less severe...

“Logic” of an EPP experiment - IV

2. OFFLINE selection: choice of a set of discriminating variables
 - cut-based selection
 - discriminating variables selection
 - multivariate classifier selection
3. The selection strategy is a crucial part of the experimentalist work: defined and optimized using simulated data samples.

“Logic” of an EPP experiment - V

- Simulated samples of events: the Montecarlo.
 - “Physics” simulation: final state with correct kinematic distributions; also dynamics in some cases is relevant.
 - “Detector” simulation: the particles are traced through the detector, interactions, decays, are simulated.
 - “Digitization”: based on the particle interactions with the detector, signals are simulated with the same features of the data.
- ➔ For every interesting final state we have MC samples with the same format of a data sample. It can be analyzed with the same program. In principle one could run on a sample without knowing if it is data or MC.
- To design a “selection” strategy for a given searched signal one needs: signal MC samples and background MC samples.

“Logic” of an EPP experiment - VI

- End of the selection: CANDIDATES sample N_{cand}
- Which relation is there between N_{cand} and N_X ?
 - **Efficiency**: not all searched final states are selected and go to the candidates sample. (Trigger efficiencies are particularly delicate to treat.)
 - **Background**: few other final states are faking good ones and go in the candidates sample.

$$\varepsilon N_X = N_{cand} - N_b$$

- where:
 - ε = efficiency ($0 < \varepsilon < 1$)
 - N_b = number of background events
- Estimate ε and N_b is a crucial work for the experimentalist and can be done either using simulation (this is typically done before the experiment) or using data themselves.

Event counting: a Poisson variable - I

- What is a Poisson process ? If we can divide the time in small intervals δt_i such that
 - $p(n=1, \delta t_i) \ll p(n=0, \delta t_i)$
 - $p(n=1, \delta t_i) = \alpha \delta t_i$
 - $p(n=1, \delta t_i)$ uncorrelated with $p(n=1, \delta t_{i+1})$
- If this happens, given a time interval Δt the number of counts n follows the Poisson distribution (λ is the only parameter)

$$p(n / \lambda) = \frac{\lambda^n e^{-\lambda}}{n!}$$

$$E[n] = \lambda$$

$$\text{var}[n] = \lambda$$

Event counting: a Poisson variable - II

- If events come in a random way (without any time structure) the event count N is a Poisson variable.
- \rightarrow if I count N , the best estimate of λ is N itself and the uncertainty is \sqrt{N}
- If N is large enough ($N > 20$) Poisson \rightarrow Gaussian. $\rightarrow N \pm \sqrt{N}$ is a 68% probability interval for N .
- If N is small (close to 0) the Gaussian limit is not ok, a specific treatment is required (see later in the course).

Efficiency: a binomial variable - I

- Bernoulli process: success/failure N proofs, $0 < n < N$, $p =$ success probability. $p \equiv \varepsilon$

$$P(n / N, p) = \binom{N}{n} p^n (1 - p)^{N-n}$$

$$E[n] = Np$$

$$\text{var}[n] = Np(1 - p)$$

- Inference: given n and N which is the best estimate of p ?
And its uncertainty ?

$$\varepsilon = \hat{p} = \frac{n}{N}$$

$$\sigma(\varepsilon) = \frac{\sigma(n)}{N} = \frac{1}{\sqrt{N}} \sqrt{\frac{n}{N} \left(1 - \frac{n}{N}\right)}$$

Efficiency: a binomial variable - II

- So: I generate N_{gen} “signal” events. If I select N_{sel} of these events out of N_{gen} , the efficiency is:

$$\varepsilon = \frac{N_{sel}}{N_{gen}}$$

$$\sigma(\varepsilon) = \frac{\sigma(N_{sel})}{N_{gen}} = \frac{1}{\sqrt{N_{gen}}} \sqrt{\frac{N_{sel}}{N_{gen}} \left(1 - \frac{N_{sel}}{N_{gen}}\right)}$$

Background N_b

- Simulation of N_{gen} “bad final states”; N_{sel} are selected. What about N_b ?
- We define the “rejection factor” $R = N_{gen} / N_{sel} > 1$
- We also need a correct normalization in this case: we need to know N_{exp} = total number of expected “bad final states” in our sample.

$$N_b = N_{sel} \frac{N_{exp}}{N_{gen}} = \frac{N_{exp}}{R}$$

$$\sigma(N_b) = \sigma(N_{sel}) \frac{N_{exp}}{N_{gen}} = \sqrt{N_{sel}} \frac{N_{exp}}{N_{gen}} = \frac{N_{exp}}{\sqrt{RN_{gen}}}$$

Summarizing

- N_{cand} : poissonian process \rightarrow the higher the better
- \mathcal{E} : binomial process \rightarrow high N_{gen} and high e
- N_b : normalized \approx poissonian process \rightarrow high R and high N_{gen} ,
low N_{exp}
- Moreover: unfortunately efficiency and background are correlated...

Efficiency-background relation

Example: selection of b-jets in ATLAS.

“b-jet” is the signal;

“light jet” is the background.

MC samples of *b-jets* and *light-jets*

Application of 5 different *selection recipes*

each with a “*free-parameter*”.

For each point I evaluate

- b-jet efficiency

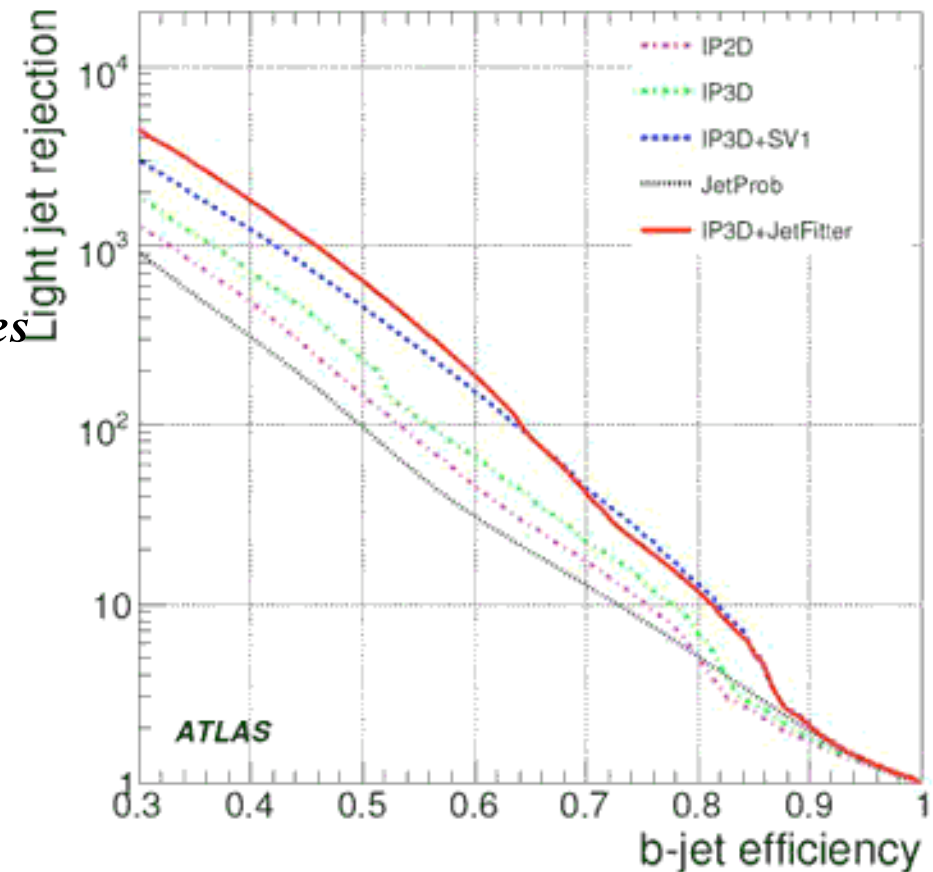
$$= N_{\text{sel}}/N_{\text{gen}} \text{ (b-jet sample)}$$

- light-jet rejection

$$= N_{\text{gen}}/N_{\text{sel}} \text{ (light-jet sample)}$$

Choice of a working point, “compromise”.

Unlucky situation: if you gain in efficiency you increase your bckg and viceversa...



How to optimize a selection ? - I

- Perfect selection is the one with
 - $\varepsilon = 1$
 - $N_b = 0$
- Intermediate situations ? Assume a given ε and a given N_b .

$$N_X = \frac{N_{cand} - N_b}{\varepsilon}$$

- Which statistical uncertainty have I on N_X ?
 - Assume a Poisson statistics to describe N_{cand} negligible uncertainty on ε and on N_b . Minimize the uncertainty on $N_{cand} - N_b$. We call:

- $N = N_{cand}$

- $B = N_b$

- $S = N - B$

$$\sigma^2(S) = \sigma^2(N) + \sigma^2(B) = N + \sigma^2(B) \approx N$$

$$\frac{S}{\sigma(S)} = \frac{S}{\sqrt{S+B}} \approx \frac{S}{\sqrt{B}}$$

How to optimize a selection ? - II

- This is the “significativity” of the signal that can be obtained. The higher is $S/\sigma(S) \approx S/\sqrt{B}$, the larger is the number of std.dev. away from 0 of my measurement of S
 - $S/\sqrt{B} < 3$ probably I have not observed any signal (my candidates can be simply a fluctuation of the background)
 - $3 < S/\sqrt{B} < 5$ probably I have observed a signal (probability of a background fluctuation very small), however no definite conclusion, more data needed.
 - $S/\sqrt{B} > 5$ observation is accepted.
- NB: S/\sqrt{B} is an approximate figure, it relies on some assumptions (see previous slide).

How to optimize a selection ? - III

- Let's define a more elaborated “score function” (widely used today).
 - Counting experiment: S and B are expected values of signal and background, N is my count. We evaluate the likelihoods in the hypothesis of $S+B$ and only B and take the “likelihood ratio”

$$L(S+B) = \frac{e^{-(S+B)}(S+B)^N}{N!}$$

$$L(B) = \frac{e^{-B}B^N}{N!}$$

$$\mathfrak{R} = \frac{L(S+B)}{L(B)} = \frac{e^{-S}(S+B)^N}{B^N} = e^{-S} \left(1 + \frac{S}{B}\right)^N$$

$$-2\log \mathfrak{R} = 2S - 2N \log \left(1 + \frac{S}{B}\right)$$

- Suppose now to count $N=S+B$ and take the square root of the $-2\log \mathfrak{R}$ evaluated above:

$$\sqrt{2\log \mathfrak{R}(N=S+B)} = \sqrt{2 \left[(S+B) \log \left(1 + \frac{S}{B}\right) - S \right]}$$

- This the so called “score function”: significativity of the signal hypothesis.

Normalization

- In order to get quantities that can be compared with theory, once we have found a given final state and counted the number of events, we need to normalize to “how many collisions” took place.
- Measurement of:
 - Luminosity (in case of colliding beam experiments);
 - Number of decaying particles (in case I want to study a decay);
 - Projectile rate and target densities (in case of a fixed target experiments).
- Several techniques to do that, all introducing additional uncertainties.
- *Absolute* vs. *Relative* measurements.

The simplest case: rate measurement

- Rate: $r = \text{counts} / \text{unit time}$ (normally given in Hz). We count N in a time Δt (neglect any possible background) and assume a Poisson process with mean λ

$$r = \frac{\lambda}{\Delta t} = \frac{N}{\Delta t} \pm \frac{\sqrt{N}}{\Delta t}$$

- NB: the higher is N , the larger is the absolute uncertainty on r but the lower the relative uncertainty.

$$\frac{\sigma(r)}{r} = \frac{1}{\sqrt{N}}$$

- Only for large N ($N > 20$) it is a 68% probability interval.

Cosmic ray “absolute” flux

- Rate in events/unit surface and time
- My detector has a surface S , I take data for a time Δt with a detector that has an efficiency ε and I count N events (again with no background). The absolute rate r is:

$$r = \frac{N}{\varepsilon \Delta t S}$$

- Uncertainty: I combine “in quadrature” all the potential uncertainties. Why in quadrature ???

$$\frac{\sigma(r)}{r} = \sqrt{\frac{1}{N} + \left(\frac{\sigma(\varepsilon)}{\varepsilon}\right)^2 + \left(\frac{\sigma(\Delta t)}{\Delta t}\right)^2 + \left(\frac{\sigma(S)}{S}\right)^2}$$

- Distinction between “*statistical*” and “*systematic*” uncertainty

Not only event counting

- Many quantities are measured (particle properties, e.g. particle mass).
- BUT in most cases they are obtained from a **FIT** to a data distribution. So, you divide events in bins and extract the quantity as a *fit parameter* → the event counting is still one major source of uncertainty → the uncertainty on the parameter depends on the statistics.
- Example:
 - Measure the mass of a “imaginary” particle of $M=5$ GeV.
 - Mass spectrum, gaussian peak over a uniform background
 - FIT in three different cases: 10^3 , 10^4 and 10^5 events selected

Mass uncertainty due to statistics

Observations:

- Poissonian uncertainty on each bin
- Reduce bin size for higher statistics
- Fit function = $A+B*\text{Gauss}(M)$
- Free parameters: A, B, M (fixed width)
- The fit is good for each statistics

Results

$N=10^3$ events:

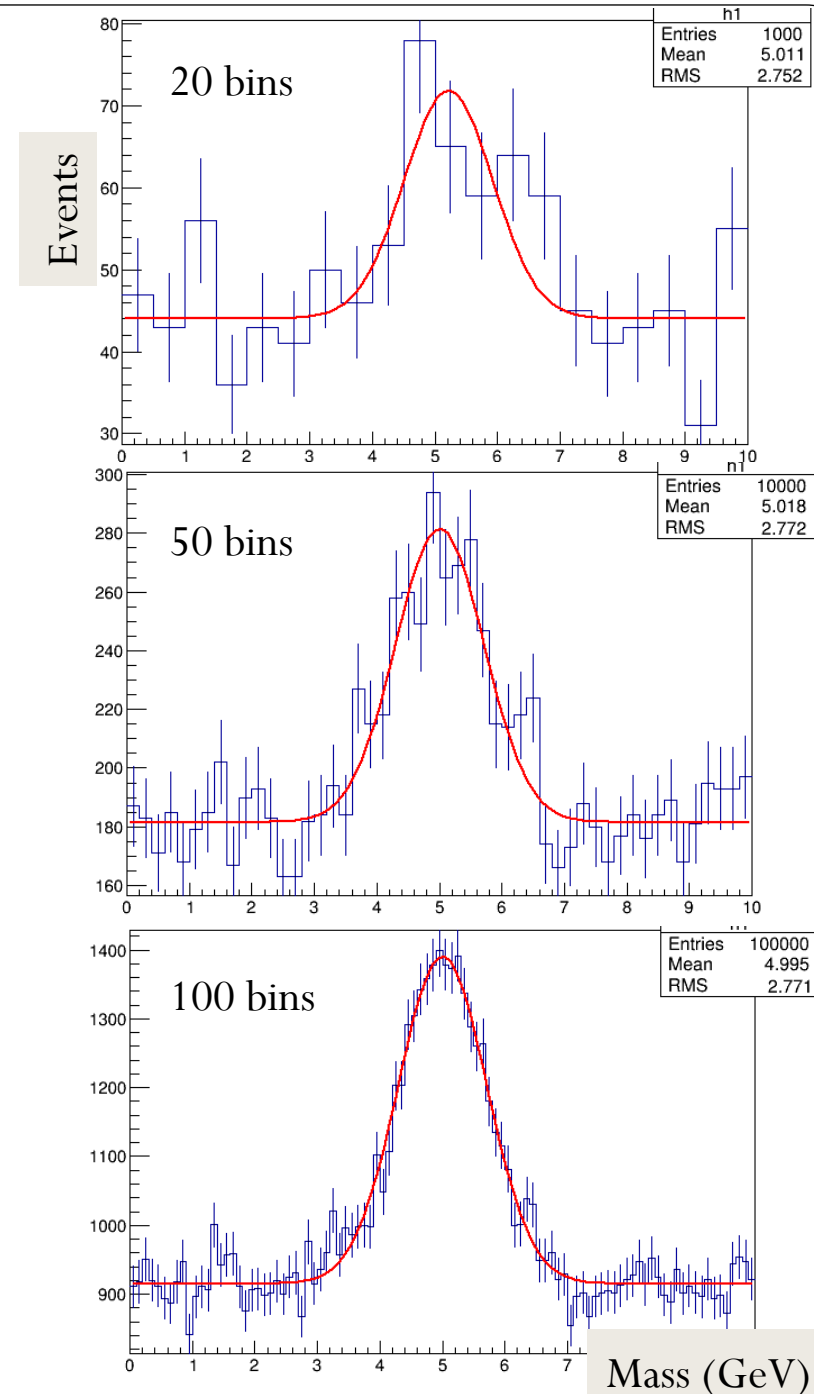
Mass = 5.22 ± 0.22 GeV, $\chi^2 = 28 / 18$ dof

$N=10^4$ events:

Mass = 5.01 ± 0.06 GeV, $\chi^2 = 38 / 48$ dof

$N=10^5$ events:

Mass = 5.02 ± 0.02 GeV, $\chi^2 = 83 / 98$ dof



Summarizing

- Steps of an EPP experiment (assuming the accelerator and the detector are there):
 - Design of a **trigger**
 - Definition of an offline **selection**
 - **Event counting** and **normalization** (including **efficiency** and **background** evaluation)
 - **Fit** of “candidate” distributions
- Uncertainties
 - Statistical due to Poisson fluctuations of the event counting
 - Statistical due to binomial fluctuations in the efficiency measurement
 - Systematic due to non perfect knowledge of detector effects.